

Wei Liu

List of Publications by Year in descending order

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8
papers

73
citations

1684188

5
h-index

2053705

5
g-index

8
all docs

8
docs citations

8
times ranked

117
citing authors

#	ARTICLE	IF	CITATIONS
1	Degradation Behaviors of 22 nm FDSOI CMOS Inverter Under Gigahertz AC Stress. , 2022, , .		0
2	Nanosecond-scale and self-heating free characterization of advanced CMOS transistors utilizing wave reflection. , 2021, , .		1
3	Ultra-Fast (ns-Scale) Characterization of NBTI Behaviors in Si pFinFETs. IEEE Journal of the Electron Devices Society, 2020, 8, 577-583.	2.1	8
4	A Fast V_{th} Measurement (FVM) Technique for NBTI Behavior Characterization. IEEE Electron Device Letters, 2018, 39, 172-175.	3.9	11
5	Sub-1ns characterization methodology for transistor electrical parameter extraction. Microelectronics Reliability, 2018, 85, 93-98.	1.7	14
6	Real-Time Polarization Switch Characterization of HfZrO ₄ for Negative Capacitance Field-Effect Transistor Applications. IEEE Electron Device Letters, 2018, 39, 1469-1472.	3.9	15
7	Ge-Based Asymmetric RRAM Enable $8F^2$ Content Addressable Memory. IEEE Electron Device Letters, 2018, 39, 1294-1297.	3.9	21
8	Effect of measurement speed (1/4s-800 ps) on the characterization of reliability behaviors for FDSOI nMOSFETs. , 2018, , .		3